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TI - NON-CONTACT IONIC CURRENT MEASURING DEVICE
IN - SHIGENAKA NAOTO; NISHIMURA EIICHI; SUZUKI KAZUMICHI
PA - HITACHI LTD
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AB - PURPOSE: To measure exactly and easily an ionic current in no contact with an ionic beam, by supplying a neutral target atom to an ionic beam line, making an ion collide with the neutral target atom, and counting a generated secondary electron by a particle detector.
- CONSTITUTION: By supplying a neutral target atom² to an ionic beam line from a neutral target atom supply device¹³, an area where an ion ¹ and the neutral target atom ² collide with each other is provided, a secondary electron ³ generated by its collision is counted by a particle detector ⁴, and an ionic current value is derived from its value. That is to say, a true ionic current value is measured in advance by a Faraday cup ⁷ which has been installed from of a secondary electron generating zone, also a secondary electron counting value corresponding to its current value is derived by the particle detector ⁴, and its calibration table is made beforehand. In this way, on the contrary, the ionic current can be derived from the counting value.
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